

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	09/782,064	MOTOYAMA ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Quoc A. Tran	2176	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

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**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

Inventor Search	Date	Exmr.
Check F22	3/24/04	(4)
Double Patent		
US PAT		
U.S PGPUB		
EPO		
JP		
DEGWGN1		
IBM_TDB		
PLUS		
FIC		
PROVISIONAL DIGESTS		
update ABOVE	8/14/04	(4)
update ABOVE	4/28/05	(4)

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